

PATENT NUMBER

U.S. UTILITY PATENT APPLICATION

J.P.E.

PATENT DATE

SCANNED

9.

APPLICATION NO. 09/973049	CONT/PRIOR F	CLASS 438 324	SUBCLASS	ART UNIT 2812	EXAMINER Hollington
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APPLICANTS

Kazunobu Miki

APPL
Semiconductor element test apparatus, and method of testing
semiconductor element using the apparatus

PTO-2040
12/89

PREPARED AND APPROVED FOR ISSUE

ISSUING CLASSIFICATION

ORIGINAL						CROSS REFERENCE(S)						
CLASS			SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION												
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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input checked="" type="checkbox"/> a) The term of this patent subsequent to _____ (date) has been disclaimed. _____ (Assistant Examiner) _____ (Date)				NOTICE OF ALLOWANCE MAILED	
	<input checked="" type="checkbox"/> b) The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____				ISSUE FEE
				Amount Due	Date Paid
<input type="checkbox"/> c) The terminal _____ months of this patent have been disclaimed. _____ (Legal Instruments Examiner) _____ (Date)				ISSUE BATCH NUMBER	

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(LABEL AREA)

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